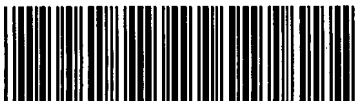


<b>Search Notes</b> 	<b>Application/Control No.</b> 10718484	<b>Applicant(s)/Patent Under Reexamination</b> BASTING ET AL.
	<b>Examiner</b> Detschel, Marissa J	<b>Art Unit</b> 2886

SEARCHED			
Class	Subclass	Date	Examiner
356	450, 454, 519	3/1/07	MJD
356	450,451,454,519	5/13/2007	JC
250	339.07-339.09	5/13/2007	JC

SEARCH NOTES		
Search Notes	Date	Examiner
Inventors search	3/1/07	MJD
Consulted Sam Turner and Andrew Lee on search and case	3/6/07	MJD
EAST search terms: pixel, degradation, damage\$, defect\$, fringe, interference, correct\$, sensitivity	3/2/07	MJD
Consulted Sam Turner on allowability	5/13/2007	JC

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
All of the above	(see search notes)	5/13/2007	JC